## Search Notes



Application/Control N	lo.

10577453

Applicant(s)/Patent Under Reexamination

VAINIO ET AL.

Examiner

MARCOS BATISTA

Art Unit 2617

## SEARCHED

Class	Subclass	Date	Examiner
455	209	3/11/2008	mb
370	286	3/11/2008	mb
348	14.01-14.14	3/11/2009	mb
455	all	3/11/2009	mb
370	all	8/26/2009	mb

SEARCH NOTES	
Search Notes	Date
osta	3/11/2008

Search Notes	Date	Examiner
Consulted with Steve D'Aghosta	3/11/2008	mb
Consulted w/ lab TA Yogesh Aggarwal	3/11/2008	mb
Consulted with Lun-Yi Lao	3/11/2008	mb
Inventor's Name Search	10/22/2008	mb
East Search	10/22/2008	mb
Consulted with Rafael Perez Gutierrez	3/11/2009	mb

## INTERFERENCE SEARCH

Class	Subclass	Date	Examiner